

Search Notes

Application/Control No.

10/675,543

Examiner

Joseph Chang

Applicant(s)/Patent under
Reexamination

HEIN ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
331	44,16 1A,107A 176,70 176,158	3/16/2005	JC
327	156,147		
375	376		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST(attached)	3/16/2005	JC